

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
10/801,487	YAN ET AL.	
Examiner	Art Unit	
IEEEDEV S I I INDGDEN	1630	

	SEARCHED				
Class	Subclass	Date	Examiner		

	INTERFERENCE SEARCHED				
Subclass	Date	Examiner			
	Subclass	Subclass Date			

SEARCH NOT (INCLUDING SEARCH)
·	DATE	EXMR
updates search in us patents and pubs via east; caplus; medline	6/30/2009	JSL
inventors names in palm	6/30/2009	JSL